QM3203S

Dual P-Ch 30V Fast Switching MOSFETs

General Description

The QM3203S is the highest performance trench P-ch MOSFETs with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The QM3203S meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Product Summery

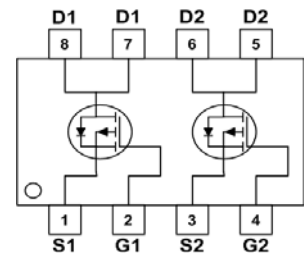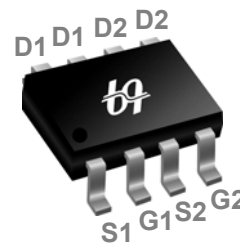| BVDSS	RDSON	ID
-30V	25mΩ	-6.5A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOP8 Pin Configuration

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	$\pm$20	V
I_D@T_A=25℃	Continuous Drain Current, -V_{GS} @ -10V[1]	-6.5	A
I_D@T_A=70℃	Continuous Drain Current, -V_{GS} @ -10V[1]	-5.2	A
I_{DM}	Pulsed Drain Current[2]	-26	A
EAS	Single Pulse Avalanche Energy[3]	176	mJ
I_{AS}	Avalanche Current	-38	A
P_D@T_A=25℃	Total Power Dissipation[4]	1.5	W
T_{STG}	Storage Temperature Range	-55 to 150	℃
T_J	Operating Junction Temperature Range	-55 to 150	℃

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient [1]	---	85	℃/W
$R_{\theta JC}$	Thermal Resistance Junction-Case[1]	---	25	℃/W

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Electrical Characteristics (T_J=25 ℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS}=0V , I_D=-250uA	-30	---	---	V
$\triangle BV_{DSS}/\triangle T_J$	BV_{DSS} Temperature Coefficient	Reference to 25℃ , I_D=-1mA	---	-0.022	---	V/℃
$R_{DS(ON)}$	Static Drain-Source On-Resistance[2]	V_{GS}=-10V , I_D=-6A	---	20	25	mΩ
		V_{GS}=-4.5V , I_D=-4A	---	32	42	
$V_{GS(th)}$	Gate Threshold Voltage	V_{GS}=V_{DS} , I_D =-250uA	-1.0	-1.5	-2.5	V
$\triangle V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	4.6	---	mV/℃
I_{DSS}	Drain-Source Leakage Current	V_{DS}=-24V , V_{GS}=0V , T_J=25℃	---	---	-1	uA
		V_{DS}=-24V , V_{GS}=0V , T_J=55℃	---	---	-5	
I_{GSS}	Gate-Source Leakage Current	V_{GS}=±20V , V_{DS}=0V	---	---	±100	nA
gfs	Forward Transconductance	V_{DS}=-5V , I_D=-6A	---	17	---	S
R_g	Gate Resistance	V_{DS}=0V , V_{GS}=0V , f=1MHz	---	13	26	Ω
Q_g	Total Gate Charge (-4.5V)	V_{DS}=-15V , V_{GS}=-4.5V , I_D=-6A	---	12.6	17.6	nC
Q_{gs}	Gate-Source Charge		---	4.8	6.7	
Q_{gd}	Gate-Drain Charge		---	4.8	6.7	
$T_{d(on)}$	Turn-On Delay Time	V_{DD}=-15V , V_{GS}=-10V , R_G=3.3Ω, I_D=-6A	---	4.6	9.2	ns
T_r	Rise Time		---	14.8	26.6	
$T_{d(off)}$	Turn-Off Delay Time		---	41	82	
T_f	Fall Time		---	19.6	39.2	
C_{iss}	Input Capacitance	V_{DS}=-15V , V_{GS}=0V , f=1MHz	---	1345	1883	pF
C_{oss}	Output Capacitance		---	194	272	
C_{rss}	Reverse Transfer Capacitance		---	158	221	

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
EAS	Single Pulse Avalanche Energy[5]	V_{DD}=-25V , L=0.1mH , I_{AS}=-20A	49	---	---	mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current[1,6]	V_G=V_D=0V , Force Current	---	---	-6.5	A
I_{SM}	Pulsed Source Current[2,6]		---	---	-26	A
V_{SD}	Diode Forward Voltage[2]	V_{GS}=0V , I_S=-1A , T_J=25℃	---	---	-1.2	V
t_{rr}	Reverse Recovery Time	I_F=-6A , dI/dt=100A/μs , T_J=25℃	---	16.3	---	nS
Q_{rr}	Reverse Recovery Charge		---	5.9	---	nC

Note :
1.The data tested by surface mounted on a 1 inch[2] FR-4 board with 2OZ copper.
2.The data tested by pulsed , pulse width $\leq$ 300us , duty cycle $\leq$ 2%
3.The EAS data shows Max. rating . The test condition is V_{DD}=-25V,V_{GS}=-10V,L=0.1mH,I_{AS}=-38A
4.The power dissipation is limited by 150℃ junction temperature
5.The Min. value is 100% EAS tested guarantee.
6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

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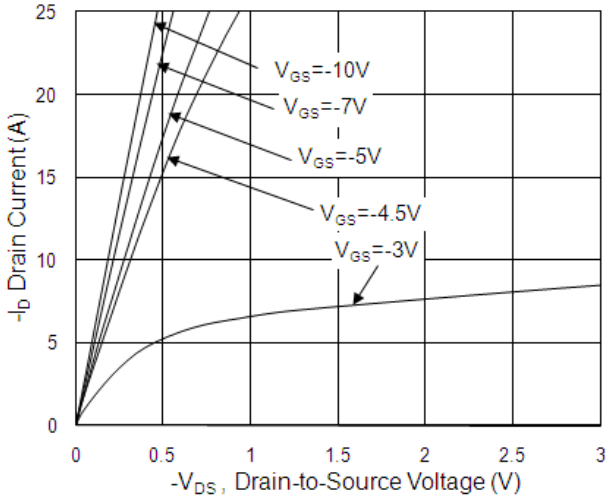
Typical Characteristics

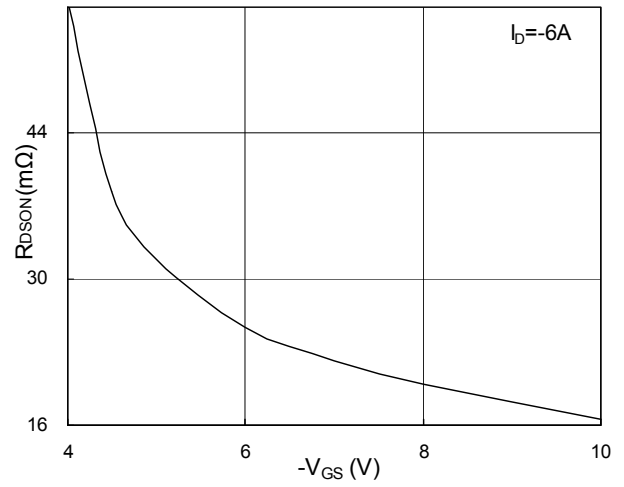**Fig.1 Typical Output Characteristics**

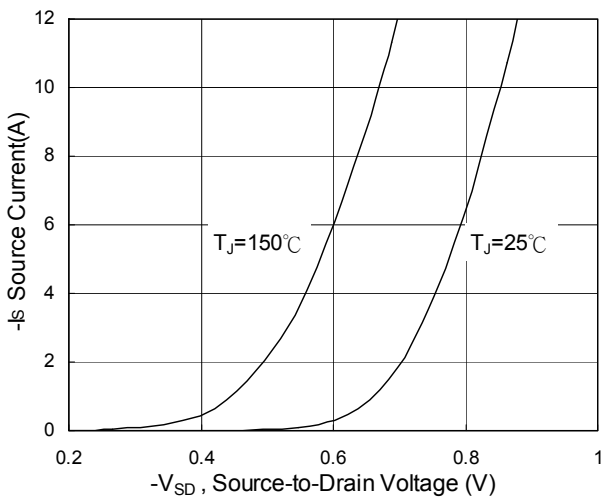**Fig.2 On-Resistance v.s Gate-Source**

Fig.3 Forward Characteristics of Reverse
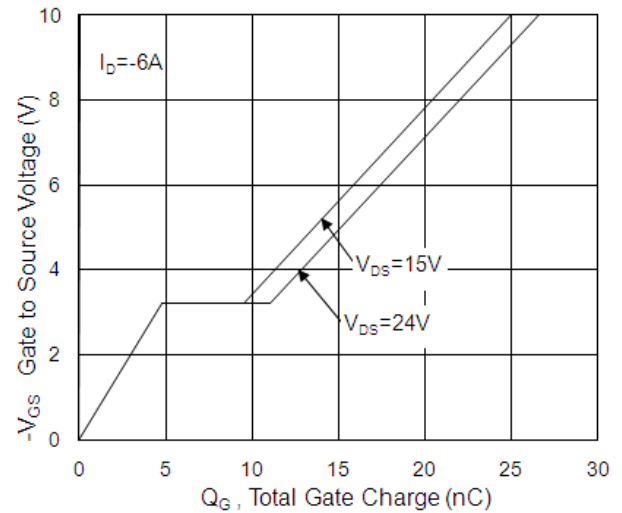
Fig.4 Gate-Charge Characteristics
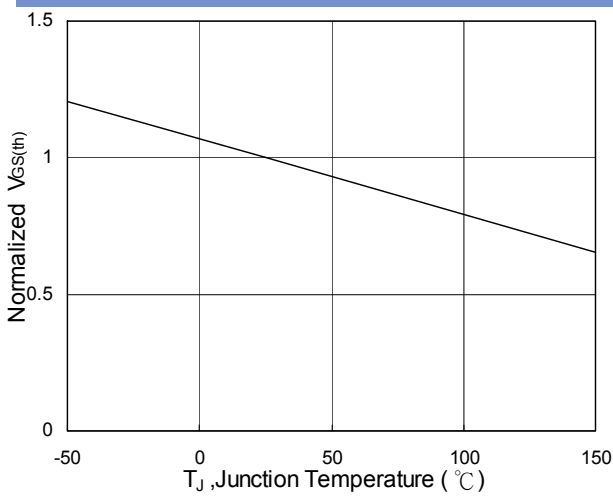
Fig.5 Normalized $V_{GS(th)}$ vs. T_J
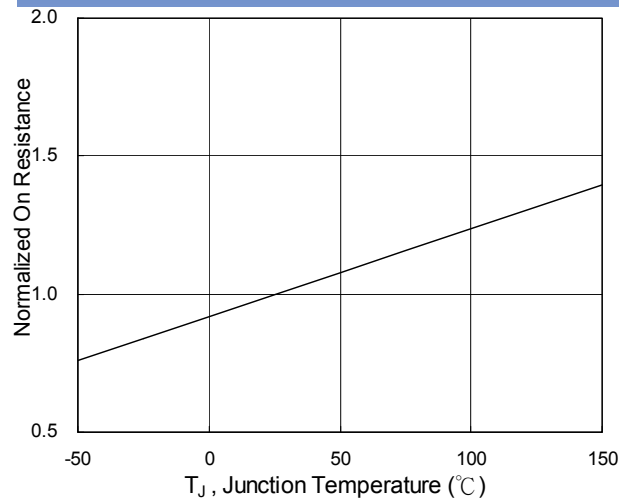
Fig.6 Normalized R_{DSON} vs. T_J

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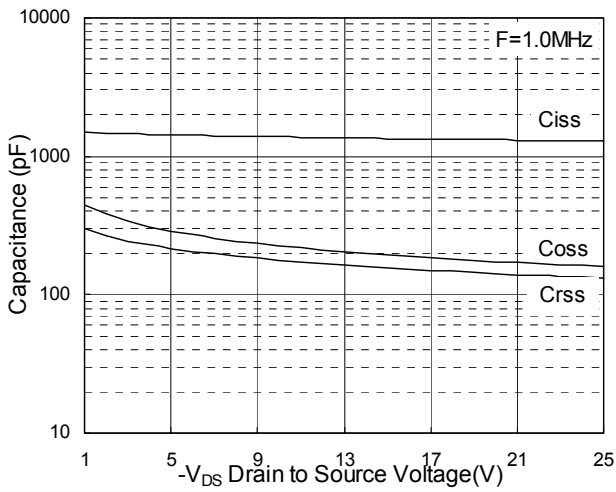
Fig.7 Capacitance
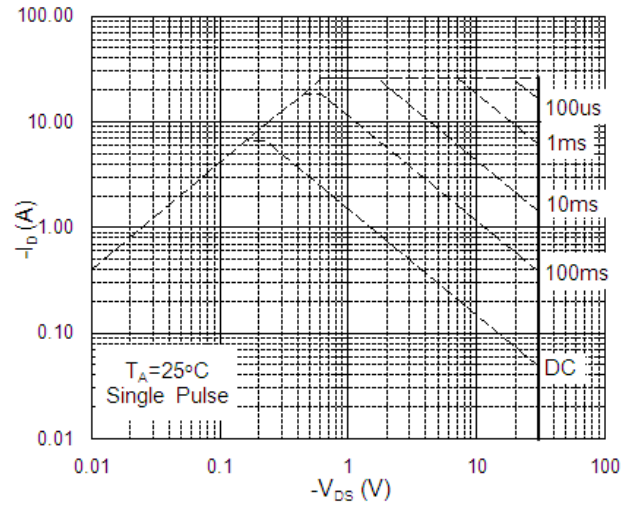
Fig.8 Safe Operating Area

$$D = T_{ON}/T$$
$$T_{Jpeak} = T_C + P_{DM} \times R_{\theta JC}$$
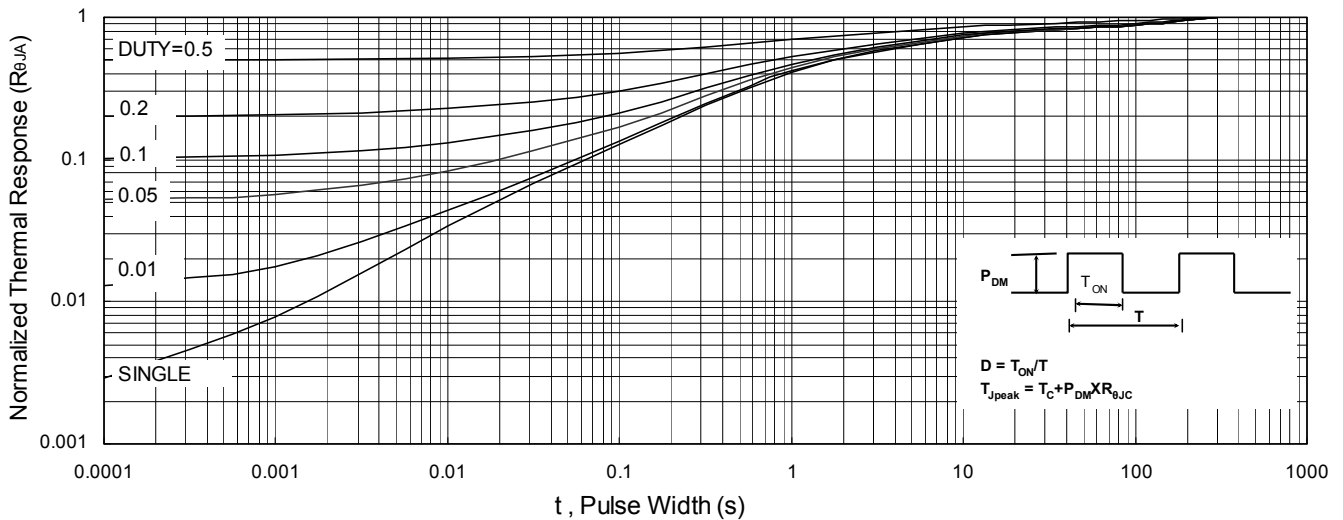
Fig.9 Normalized Maximum Transient Thermal Impedance
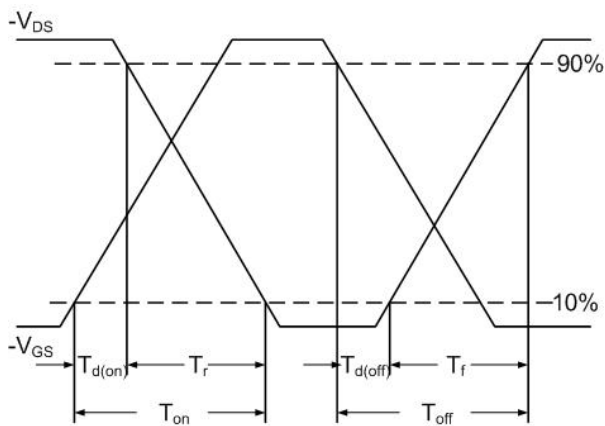
Fig.10 Switching Time Waveform

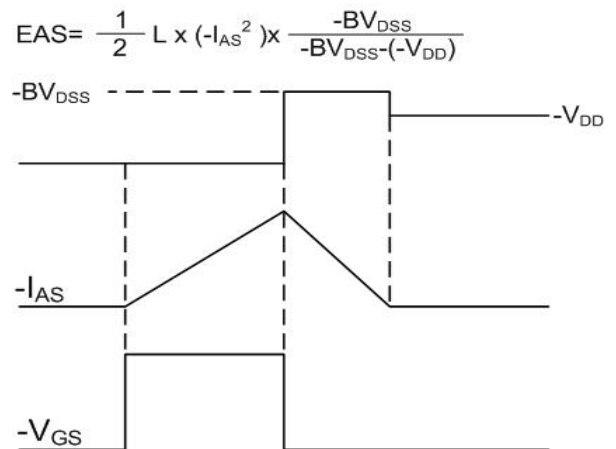$$EAS = \frac{1}{2} L \times (-I_{AS}^2) \times \frac{-BV_{DSS}}{-BV_{DSS}-(-V_{DD})}$$

Fig.11 Unclamped Inductive Switching Waveform

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